

Notice of References Cited	Application/Control No. 10/658,768	Applicant(s)/Patent Under Reexamination EGAWA ET AL.	
	Examiner TuyetLien (Lien) T. Tran	Art Unit 2179	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-2003/0152904 A1	08-2003	Doty, Thomas R. JR.	434/350
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	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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